

Data sheet acquired from Harris Semiconductor SCHS173C

November 1997 - Revised October 2003

High-Speed CMOS Logic 8-Bit Addressable Latch

Features

- · Buffered Inputs and Outputs
- · Four Operating Modes
- Typical Propagation Delay of 15ns at $V_{CC} = 5V$, $C_1 = 15pF$, $T_{\Delta} = 25^{\circ}C$
- Fanout (Over Temperature Range)
- Wide Operating Temperature Range ... -55°C to 125°C
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- HC Types
 - 2V to 6V Operation
 - High Noise Immunity: N_{IL} = 30%, N_{IH} = 30% of V_{CC} at V_{CC} = 5V
- HCT Types
 - 4.5V to 5.5V Operation
 - Direct LSTTL Input Logic Compatibility,
 V_{IL}= 0.8V (Max), V_{IH} = 2V (Min)
 - CMOS Input Compatibility, $I_I \le 1\mu A$ at V_{OL} , V_{OH}

Description

The 'HC259 and 'HCT259 Addressable Latch features the low-power consumption associated with CMOS circuitry and has speeds comparable to low-power Schottky.

This latches three active modes and one reset mode. When both the Latch Enable ($\overline{\text{LE}}$) and Master Reset ($\overline{\text{MR}}$) inputs are low (8-line Demultiplexer mode) the output of the addressed latch follows the Data input and all other outputs are forced low. When both $\overline{\text{MR}}$ and $\overline{\text{LE}}$ are high (Memory Mode), all outputs are isolated from the Data input, i.e., all latches hold the last data presented before the $\overline{\text{LE}}$ transition from low to high. A condition of $\overline{\text{LE}}$ low and $\overline{\text{MR}}$ high (Addressable Latch mode) allows the addressed latch's output to follow the data input; all other latches are unaffected. The Reset mode (all outputs low) results when $\overline{\text{LE}}$ is high and $\overline{\text{MR}}$ is low.

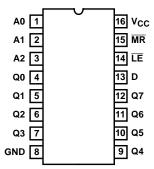
Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE
CD54HC259F3A	-55 to 125	16 Ld CERDIP
CD54HCT259F3A	-55 to 125	16 Ld CERDIP
CD74HC259E	-55 to 125	16 Ld PDIP
CD74HC259M	-55 to 125	16 Ld SOIC
CD74HC259MT	-55 to 125	16 Ld SOIC
CD74HC259M96	-55 to 125	16 Ld SOIC
CD74HCT259E	-55 to 125	16 Ld PDIP
CD74HCT259M	-55 to 125	16 Ld SOIC
CD74HCT259MT	-55 to 125	16 Ld SOIC
CD74HCT259M96	-55 to 125	16 Ld SOIC

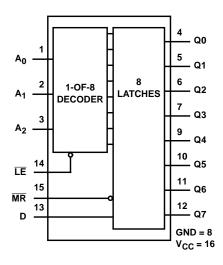
NOTE: When ordering, use the entire part number. The suffix 96 denotes tape and reel. The suffix T denotes a small-quantity reel of 250.

Pinout

CD54HC259, CD54HCT259 (CERDIP) CD74HC259, CD74HCT259 (PDIP, SOIC) TOP VIEW



Functional Diagram



TRUTH TABLE

INP	UTS	OUTPUT OF	EAGU OTUED	
MR	LE	ADDRESS LATCH	EACH OTHER OUTPUT	FUNCTION
Н	L	D	Q _{io}	Addressable Latch
Н	Н	Q _{io}	Q _{io}	Memory
L	Г	D	L	8-Line Demultiplexer
L	Н	L	L	Reset

H = High Voltage Level

L = Low Voltage Level

D = The level at the data input

 Q_{iO} = The level of Q_i (i = 0, 1...7, as appropriate) before the indicated steady-state input conditions were established.

LATCH SELECTION TABLE

SI	ELECT INPUT	rs	LATCH
A2	A 1	A0	ADDRESSED
L	L	L	0
L	L	Н	1
L	Н	L	2
L	Н	Н	3
Н	L	L	4
Н	L	Н	5
Н	Н	L	6
Н	Н	Н	7

Absolute Maximum Ratings

DC Supply Voltage, V $_{CC}$... -0.5V to 7V DC Input Diode Current, I $_{IK}$ For V $_{I}$ < -0.5V or V $_{I}$ > V $_{CC}$ + 0.5V ... ± 20 mA DC Output Diode Current, I $_{OK}$ For V $_{O}$ < -0.5V or V $_{O}$ > V $_{CC}$ + 0.5V ... ± 20 mA DC Drain Current, per Output, I $_{O}$ For -0.5V < V $_{O}$ < V $_{CC}$ + 0.5V ... ± 25 mA DC Output Source or Sink Current per Output Pin, I $_{O}$ For V $_{O}$ > -0.5V or V $_{O}$ < V $_{CC}$ + 0.5V ... ± 25 mA DC V $_{CC}$ or Ground Current, I $_{CC}$ or I $_{GND}$... ± 25 mA

Thermal Information

Thermal Resistance (Typical, Note 1)	θ _{JA} (°C/W)
E (PDIP) Package	67
M (SOIC) Package	73
Maximum Junction Temperature	150 ^o C
Maximum Storage Temperature Range65	5°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C
(SOIC - Lead Tips Only)	

Operating Conditions

Temperature Range, T _A)
HC Types2V to 6V	,
• •	
HCT Types	/
DC Input or Output Voltage, V _I , V _O	5
Input Rise and Fall Time	
2V)
4.5V 500ns (Max)
6V)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. The package thermal impedance is calculated in accordance with JESD 51-7.

DC Electrical Specifications

		TES CONDI		V _{CC}		25°C		-40°C T	O 85°C	-55°C T	O 125°C		
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS	
HC TYPES													
High Level Input	V _{IH}	-	-	2	1.5	-	-	1.5	-	1.5	-	V	
Voltage				4.5	3.15	-	-	3.15	-	3.15	-	V	
				6	4.2	-	-	4.2	-	4.2	-	V	
Low Level Input	V _{IL}	-	-	2	-	-	0.5	-	0.5	-	0.5	V	
Voltage				4.5	-	-	1.35	-	1.35	-	1.35	V	
				6	-	-	1.8	-	1.8	-	1.8	V	
High Level Output	V _{OH}	V _{IH} or V _{IL}	-0.02	2	1.9	-	-	1.9	-	1.9	-	V	
Voltage CMOS Loads			-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V	
Owied Edda			-0.02	6	5.9	-	-	5.9	-	5.9	-	V	
High Level Output	7			-	-	-	-	-	-	-	-	-	V
Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V	
TTE Education			-5.2	6	5.48	-	-	5.34	-	5.2	-	V	
Low Level Output	V _{OL}	V _{IH} or V _{IL}	0.02	2	-	-	0.1	-	0.1	-	0.1	V	
Voltage CMOS Loads			0.02	4.5	-	-	0.1	-	0.1	-	0.1	V	
Owied Edda			0.02	6	-	-	0.1	-	0.1	-	0.1	V	
Low Level Output			-	-	-	-	-	-	-	-	-	V	
Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V	
	<u> </u>		5.2	6	-	-	0.26	-	0.33	-	0.4	V	
Input Leakage Current	Ι _Ι	V _{CC} or GND	-	6	-	-	±0.1	-	±1	-	±1	μА	

DC Electrical Specifications (Continued)

		TES CONDI		Vcc		25°C		-40°C 1	O 85°C	-55°C T	O 125°C	
PARAMETER	SYMBOL	V _I (V)	I _O (mA)	(V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
Quiescent Device Current	Icc	V _{CC} or GND	0	6	-	-	8	-	80	-	160	μΑ
HCT TYPES												
High Level Input Voltage	V _{IH}	-	-	4.5 to 5.5	2	-	-	2	-	2	-	V
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	-	0.8	-	0.8	-	0.8	V
High Level Output Voltage CMOS Loads	V _{OH}	V _{IH} or V _{IL}	-0.02	4.5	4.4	-	-	4.4	-	4.4	-	V
High Level Output Voltage TTL Loads			-4	4.5	3.98	-	-	3.84	-	3.7	-	V
Low Level Output Voltage CMOS Loads	V _{OL}	V _{IH} or V _{IL}	0.02	4.5	-	-	0.1	-	0.1	-	0.1	V
Low Level Output Voltage TTL Loads			4	4.5	-	-	0.26	-	0.33	-	0.4	V
Input Leakage Current	lį	V _{CC} and GND	0	5.5	-		±0.1	-	±1	-	±1	μΑ
Quiescent Device Current	l _{CC}	V _{CC} or GND	0	5.5	-	-	8	-	80	-	160	μΑ
Additional Quiescent Device Current Per Input Pin: 1 Unit Load	ΔI _{CC} (Note 2)	V _{CC} -2.1	-	4.5 to 5.5	-	100	360	-	450	-	490	μА

NOTE:

HCT Input Loading Table

INPUT	UNIT LOADS
A0 - A2, LE	1.5
D	1.2
MR	0.75

NOTE: Unit Load is ΔI_{CC} limit specified in DC Electrical Table, e.g., 360µA max at $25^{o}C.$

Prerequisite for Switching Specifications

			25°C		-40°C TO 85°C			-55°C TO 125°C				
PARAMETER	SYMBOL	V _{CC} (V)	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
HC TYPES				-	_	-	-	_		-		_
Pulse Width	t _{WL}											
ΙĒ		2	70	-	-	90	-	-	105	-	-	ns
		4.5	14	-	-	18	-	-	21	-	-	ns
		6	12	-	-	15	-	-	18	-	-	ns

^{2.} For dual-supply systems theoretical worst case ($V_I = 2.4V$, $V_{CC} = 5.5V$) specification is 1.8mA.

Prerequisite for Switching Specifications (Continued)

				25°C		-40	°C TO 85	o°C	-55 ⁰			
PARAMETER	SYMBOL	V _{CC} (V)	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
MR	t _{WL}	2	70	-	-	90	-	-	105	-	-	ns
		4.5	14	-	-	18	-	-	21	-	-	ns
		6	12	-	-	15	-	-	18	-	-	ns
Setup Time	t _{SU}											
D to LE A to LE		2	80	-	-	100	-	-	120	-	-	ns
A to LE		4.5	16	-	1	20	-	-	24	-	-	ns
		6	14	-	-	17	-	-	20	-	-	ns
Hold Time	t _H											
D to LE A to LE		2	0	-	-	0	-	-	0	-	-	ns
AUL		4.5	0	-	-	0	-	-	0	-	-	ns
		6	0	-	-	0	-	-	0	-	-	ns
HCT TYPES												
Pulse Width LE MR	t _{WL}	4.5	18	-	-	23	-	-	27	-	-	ns
Setup Time D to LE A to LE	t _{SU}	4.5	17	-	-	21	-	-	26	-	-	ns
Hold Time D to LE A to LE	tH	4.5	0	-	-	0	-	-	0	-	-	ns

Switching Specifications $C_L = 50 pF$, Input t_f , $t_f = 6 ns$

		TEST		25°C				С ТО °С	-55 ⁰ 125		
PARAMETER	SYMBOL	CONDITIONS	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
HC TYPES		-									
Propagation Delay	t _{PHL}	C _L = 50pF									
D to Q			2	-	-	185	-	230	-	280	ns
			4.5	-	-	37	-	46	-	56	ns
		C _L = 15pF	5	-	15	-	-	-	=	-	ns
		C _L = 50pF	6	-	-	31	-	39	=	48	ns
LE to Q	t _{PHL}	C _L = 50pF	2	-	-	170	-	215	=	255	ns
			4.5	-	-	34	-	43	=	51	ns
		C _L = 15pF	5	-	14	-	-	-	-	-	ns
		C _L = 50pF	6	-	-	29	-	37	=	43	ns

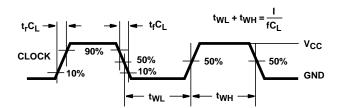
Switching Specifications $C_L = 50pF$, Input t_r , $t_f = 6ns$ (Continued)

		TEST			25°C		-40 ⁰ 85	С ТО °С	-55°C TO 125°C		
PARAMETER	SYMBOL	CONDITIONS	V _{CC} (V)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNITS
A to Q	t _{PHL}	C _L = 50pF	2	-	-	185	-	230	-	280	ns
			4.5	-	-	37	-	46	-	56	ns
		C _L = 15pF	5	-	15	-	-	-	-	-	ns
		C _L = 50pF	6	i	-	31	-	39	-	48	ns
MR to Q	t _{PHL} , t _{PLH}	C _L = 50pF	2	i	-	155	ı	195	ı	235	ns
			4.5	-	-	31	-	39	-	47	ns
		C _L = 15pF	5	-	13	-	-	-	-	-	ns
		C _L = 50pF	6	-	-	26	-	33	-	40	ns
Output Transition Time	t _{THL} , t _{TLH}	C _L = 50pF	2	-	-	75	-	95	-	110	ns
			4.5	-	-	15	-	19	-	22	ns
			6	-	-	13	-	16	-	19	ns
Power Dissipation Capacitance (Notes 3, 4)	C _{PD}	C _L = 15pF	5	-	21	-	-	-	-	-	pF
Input Capacitance	Cl	C _L = 50pF	-	10	-	10	-	10	-	10	pF
HCT TYPES											
Propagation Delay D to Q	t _{PHL} , t _{PLH}	C _L = 50pF	4.5	-	-	39	-	49	-	59	ns
		C _L = 15pF	5	-	16	-	-	-	-	-	ns
LE to Q		C _L = 50pF	4.5	-	-	38	-	48	-	57	ns
		C _L = 15pF	5	-	16	-	-	-	-	-	ns
A to Q		C _L = 50pF	4.5	-	-	41	-	51	-	61	ns
		C _L = 15pF	5	-	17	-	-	-	-	-	ns
MR to Q		C _L = 50pF	4.5	-	-	39	-	49	-	59	ns
		C _L = 15pF	5	-	16	-	-	-	-	-	ns
Power Dissipation Capacitance (Notes 3, 4)	C _{PD}	C _L = 15pF	5	-	22	-	-	-	-	-	pF
Input Capacitance	Cl	C _L = 50pF	-	10	-	10	-	10	-	10	pF
Output Transition Time	t _{THL} , t _{TLH}	C _L = 50pF	4.5	-	-	15	-	19	-	22	ns

 ^{3.} C_{PD} is used to determine the dynamic power consumption, per package.
 4. P_D = C_{PD} V_{CC}² f_i + ∑ C_L V_{CC}² f_O where f_i = Input Frequency, f_O = Output Frequency, C_L = Output Load Capacitance, V_{CC} = Supply Voltage.

Test Circuits and Waveforms

PULSE WIDTH



NOTE: Outputs should be switching from 10% V $_{CC}$ to 90% V $_{CC}$ in accordance with device truth table. For f $_{MAX}$, input duty cycle = 50%.

ccordance with device truth table. For f_{MAX}, input duty cycle = 50% FIGURE 1. HC CLOCK PULSE RISE AND FALL TIMES AND

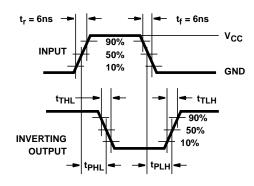


FIGURE 3. HC TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

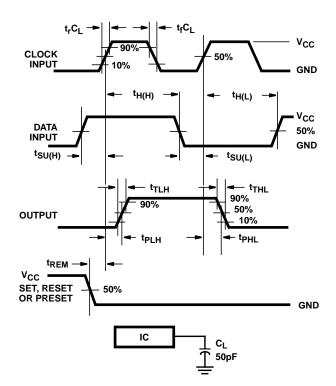
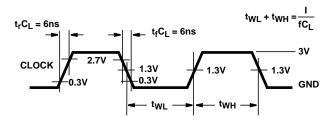


FIGURE 5. HC SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS



NOTE: Outputs should be switching from 10% V_{CC} to 90% V_{CC} in accordance with device truth table. For f_{MAX} , input duty cycle = 50%.

FIGURE 2. HCT CLOCK PULSE RISE AND FALL TIMES AND PULSE WIDTH

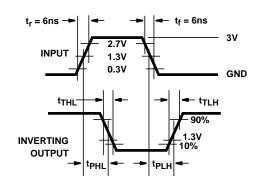


FIGURE 4. HCT TRANSITION TIMES AND PROPAGATION DELAY TIMES, COMBINATION LOGIC

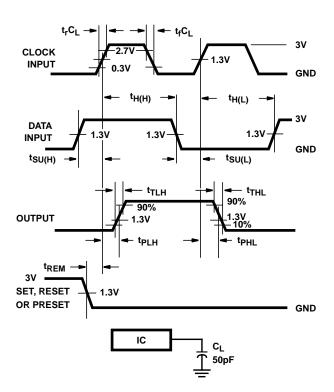
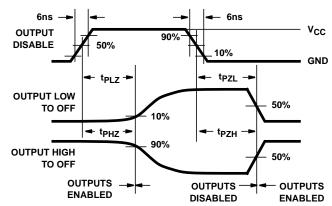


FIGURE 6. HCT SETUP TIMES, HOLD TIMES, REMOVAL TIME, AND PROPAGATION DELAY TIMES FOR EDGE TRIGGERED SEQUENTIAL LOGIC CIRCUITS

Test Circuits and Waveforms (Continued)



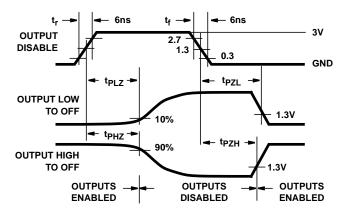
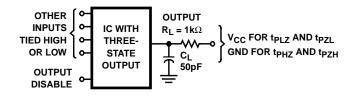


FIGURE 7. HC THREE-STATE PROPAGATION DELAY WAVEFORM

FIGURE 8. HCT THREE-STATE PROPAGATION DELAY WAVEFORM



NOTE: Open drain waveforms t_{PLZ} and t_{PZL} are the same as those for three-state shown on the left. The test circuit is Output $R_L = 1k\Omega$ to V_{CC} , $C_L = 50pF$.

FIGURE 9. HC AND HCT THREE-STATE PROPAGATION DELAY TEST CIRCUIT





25-Sep-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type		Pins		Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
5962-8985201EA	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8985201EA CD54HCT259F3A	Samples
CD54HC259F3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	8551901EA CD54HC259F3A	Samples
CD54HCT259F3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	5962-8985201EA CD54HCT259F3A	Samples
CD74HC259E	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC259E	Samples
CD74HC259EE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HC259E	Samples
CD74HC259M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259M96E4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259M96G4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259ME4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259MG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259MT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259MTE4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HC259MTG4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HC259M	Samples
CD74HCT259E	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT259E	Samples
CD74HCT259EE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD74HCT259E	Samples
CD74HCT259M	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples





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Orderable Device	Status	Package Type	_	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)		(3)		(4/5)	
CD74HCT259M96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259M96E4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259M96G4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259ME4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259MG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259MT	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259MTE4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples
CD74HCT259MTG4	ACTIVE	SOIC	D	16	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	HCT259M	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



PACKAGE OPTION ADDENDUM

25-Sep-2013

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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OTHER QUALIFIED VERSIONS OF CD54HC259, CD54HCT259, CD74HC259, CD74HCT259:

Catalog: CD74HC259, CD74HCT259

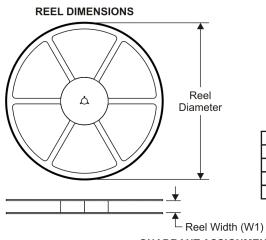
Military: CD54HC259, CD54HCT259

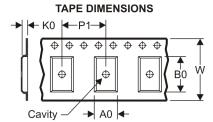
NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications



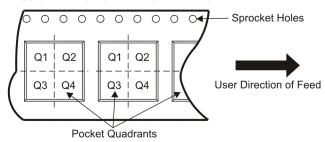
TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

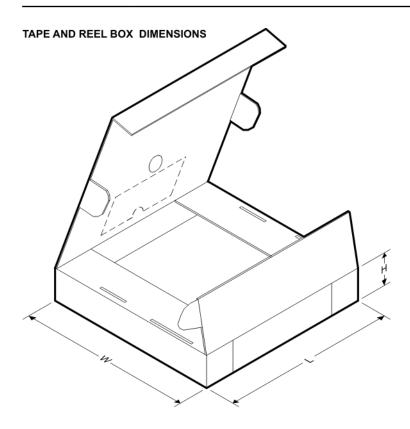
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HC259M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD74HCT259M96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1





*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HC259M96	SOIC	D	16	2500	333.2	345.9	28.6
CD74HCT259M96	SOIC	D	16	2500	333.2	345.9	28.6

14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDS0-G16)

PLASTIC SMALL OUTLINE

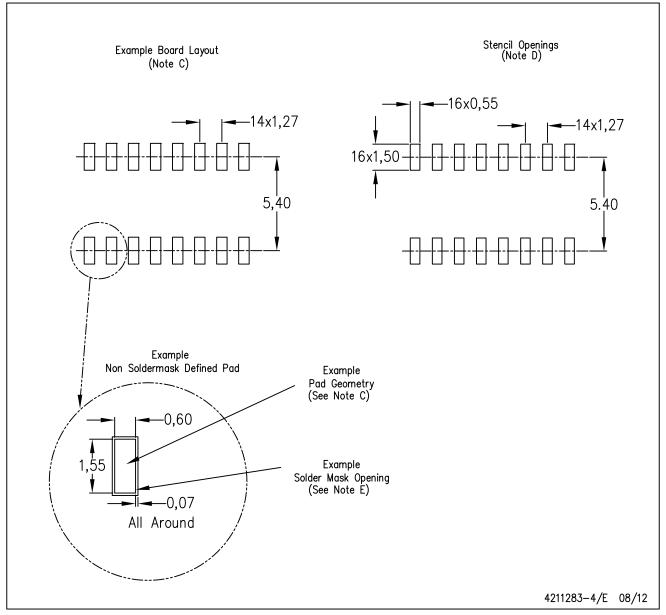


- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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